

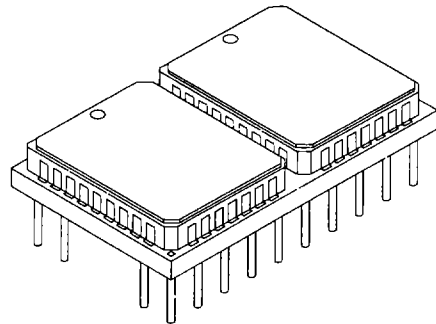
SR
11-3-94

DESCRIPTION:

The DPE32X16A is a high-performance Electrically Erasable and Programmable Read Only Memory (EEPROM) module and may be organized as 32K X 16, or 64K X 8.

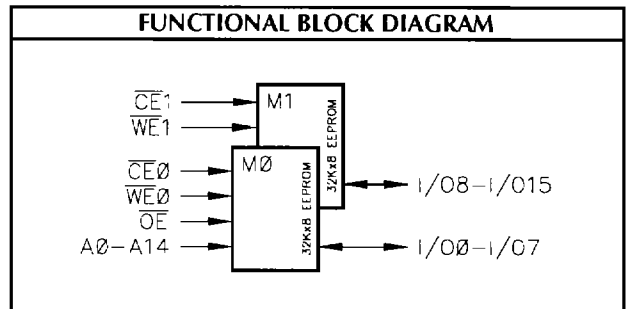
The module is built with two low-power CMOS 32K X 8 EEPROMs. The two chip enables are used for individual BW* selection. The DPE32X16A is ideally suited for those computer systems having 16-bit architectures.

The DPE32X16A contains a 64-BW page register to allow writing of up to 64 BWs simultaneously. During a write cycle, the address and 1 to 64 BWs of data are internally latched, freeing the address and data bus for other operations. Following the initiation of a write cycle, the module will automatically write the latched data using an internal control timer. The end of a write cycle can be detected by DATA Polling of the most significant data bit in each byte. Once the end of a write cycle has been detected, a new access for a read or write can begin.



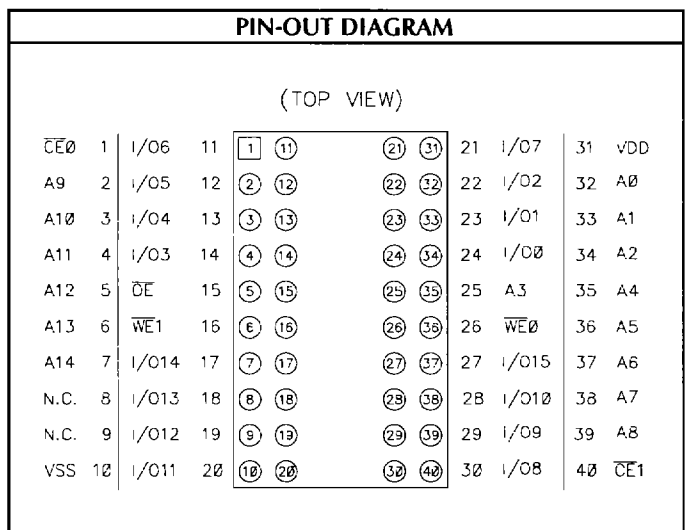
FEATURES:

- Fast Access Times: 55, 70, 90, 120, 150, 200, 250ns
- Automatic Page Write Operation:
Internal Address and Data Latches
Internal Control Timer
- Fast Write Cycle Times:
Page Write Cycle Time: 10ms maximum
1 to 64 BW* Page Write Operation
- DATA Polling for End of Write Detection
- High Reliability CMOS Technology
Endurance: 10⁴ Cycles
Data Retention: 10 years
- Single +5V Power Supply, ±10% Tolerance
- CMOS and TTL Compatible Inputs and Outputs
- Available with All Semiconductor Components
Compliant to MIL-STD-883; Class B
- 40-Pin PGA (Grid Array) Package



PIN NAMES	
A0 - A14	Address Inputs
I/O0 - I/O15	Data In/Out
CE0, CE1	Chip Enables
WE0, WE1	Write Enables
OE	Output Enable
VDD	Power (+5V)
VSS	Ground
N.C.	No Connect

* Byte or Word (BW)



ABSOLUTE MAXIMUM RATINGS ¹			
Symbol	Parameter	Value	Unit
T _{STG}	Storage Temperature	-65 to +125	°C
T _{BIAS}	Temperature Under Bias	-55 to +125	°C
V _{DD}	Supply Voltage ²	-0.5 to +7.0	°C
V _{I/O}	Input/Output Voltage ²	-0.5 to +7.0	V

RECOMMENDED OPERATING RANGE ¹						
Symbol	Characteristic	Min.	Typ.	Max.	Unit	
V _{DD}	Supply Voltage ⁴	4.5	5.0	5.5	V	
V _{IH}	Input HIGH Voltage	2.2		V _{DD} +0.3	V	
V _{IL}	Input LOW Voltage	-0.1 ²		0.8	V	
T _A	Operating Temperature	C	0	+25	+70	°C
		I	-40	+25	+85	
		M/B	-55	+25	+125	

AC TEST CONDITIONS	
Input Pulse Levels	0V to 3.0V
Input Pulse Rise and Fall Times	5ns*
Input and Output Timing Reference Levels	1.5V

* Transition between 0.8V and 2.2V.

OUTPUT LOAD		
Load	C _L	Parameters Measured
1	100pF	except t _{DF}
2	5pF	t _{DF}

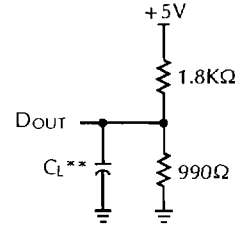
TRUTH TABLE				
Mode	CE	OE	WE	I/I Pin
Standby	H	X	X	HIGH-Z
Read	L	L	H	D _{OUT}
Write	L	H	L	D _{IN}
Write Inhibit	X	L	X	HIGH-Z
Write Inhibit	X	X	H	HIGH-Z

L = LOW H = HIGH X = Don't Care

CAPACITANCE ³ : T _A = 25°C, F = 1.0MHz				
Symbol	Parameter	Max.	Unit	Condition
C _{CE}	Chip Enable	15	pF	V _{IN} = 0V
C _{ADR}	Address Input	35		
C _{WE}	Write Enable	15		
C _{OE}	Output Enable	35		
C _{I/O}	Data Input/Output	25		

Figure 1. Output Load

** Including Probe and Jig Capacitance.

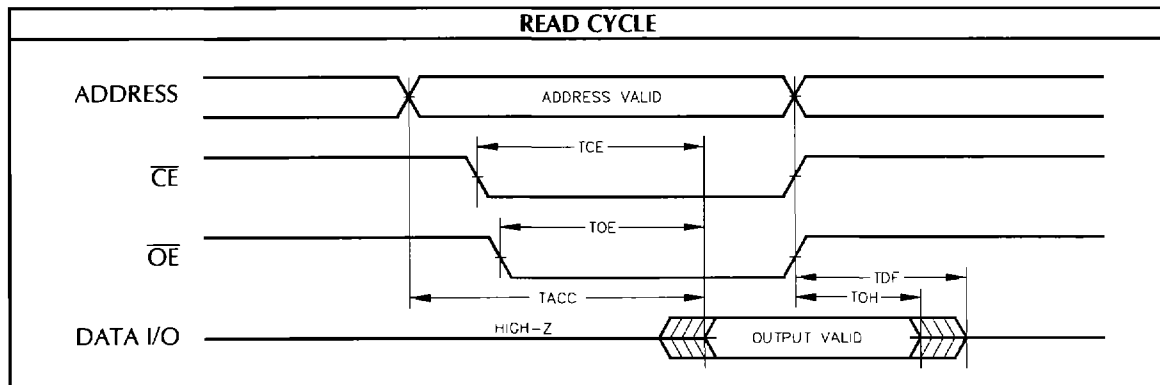


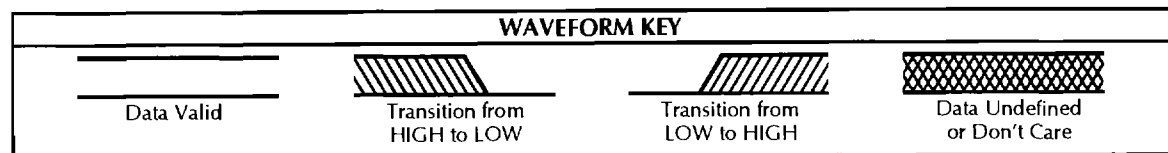
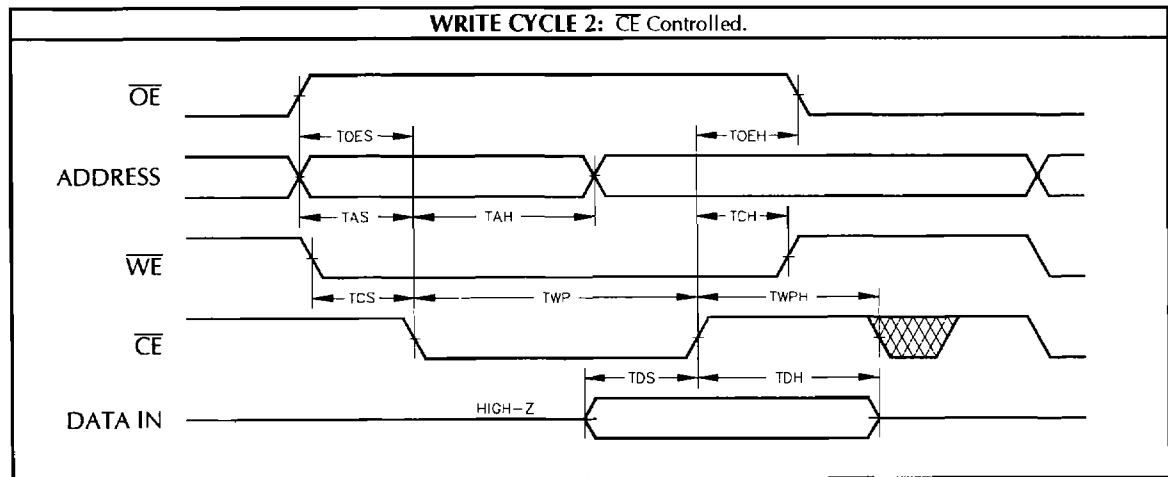
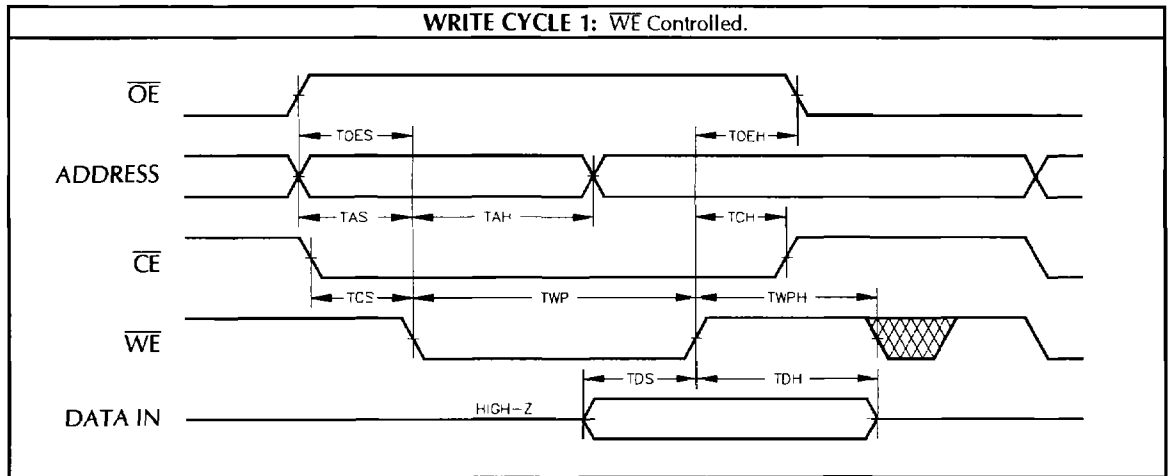
DC OPERATING CHARACTERISTICS: Over operating ranges							
Symbol	Characteristics	Test Conditions	X16		X8		Unit
			Min.	Max.	Min.	Max.	
I _{IN}	Input Leakage Current	V _{IN} = V _{DD} Max.	-10	+10	-10	+10	μA
I _{OUT}	Output Leakage Current	V _{OUT} = V _{DD} Max.	-10	+10	-20	+20	μA
I _{CC}	Operating Supply Current	CE = OE = V _{IL} , all I/O = 0mA, f = trc Min.	150 - 250ns	160	90		mA
			55 - 90ns	160	140		
I _{S81}	V _{DD} Standby Current (TTL)	CE = V _{IH}	150 - 250ns	6	6		mA
			55 - 90ns	120	120		
I _{S82}	V _{DD} Standby Current (CMOS)	CE = V _{DD} ± 0.3V	150 - 250ns	0.75	0.75		mA
			55 - 90ns	120	120		
V _{OL}	Output LOW Voltage	I _{OUT} = 2.1mA		0.45	0.45		V
V _{OH}	Output HIGH Voltage	I _{OUT} = -400μA	2.4		2.4		V

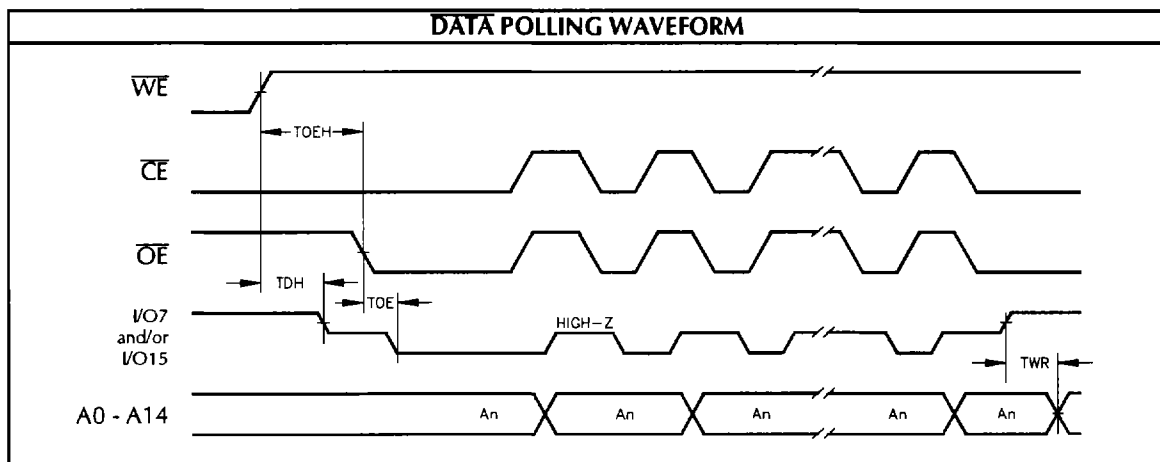
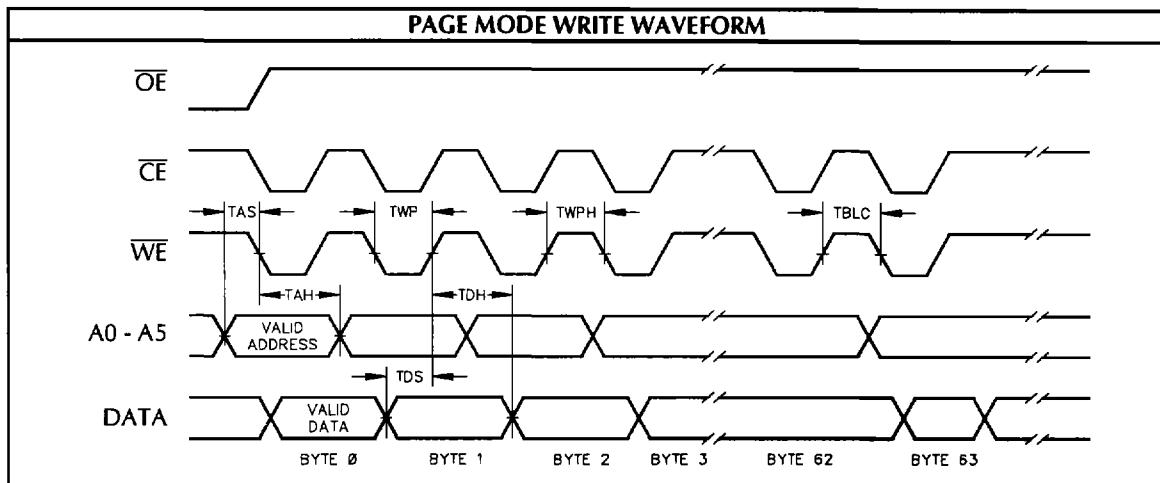
AC OPERATING CONDITIONS AND CHARACTERISTICS - READ CYCLE: Over operating ranges ^{5, 6}																	
No.	Symbol	Parameter	55ns		70ns		90ns		120ns		150ns		200ns		250ns		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.			
1	t _{ACC}	Address to Output Valid		55		70		90		120		150		200		250	ns
2	t _{CE}	Chip Enable to Output Valid		55		70		90		120		150		200		250	ns
3	t _{OE}	Output Enable to Output Valid		30		35		45		50		70		80		100	ns
4	t _{DF}	Chip Enable or Output Enable to Output Float ³		30		35		45		50		55		55		55	ns
5	t _{OH}	Output Hold from Chip Enable, Output Enable, or Address, Whichever Occurs First	0		0		0		0		0		0		0		ns
6	t _{PUR}	Power-up to Read Operation		100		100		100		100		100		100		100	μs

AC OPERATING CONDITIONS AND CHARACTERISTICS - WRITE CYCLE: Over operating ranges ^{5, 6}					
No.	Symbol	Parameter	Min.	Max.	Unit
7	t _{WC}	Write Cycle Time		10	ms
8	t _{AS}	Address Set-up Time *	0		ns
9	t _{AH}	Address Hold Time	50		ns
10	t _{CS}	Chip Select Set-up Time	0		ns
11	t _{CH}	Chip Select Hold Time	0		ns
12	t _{WP}	Write Pulse Width (WE or CE)	100		ns
13	t _{DS}	Data Set-up Time	50		ns
14	t _{DH}	Data Hold Time	0		ns
15	t _{OES}	Output Enable Set-up Time	0		ns
16	t _{OEH}	Output Enable Hold Time	0		ns
17	t _{WPH}	Write Pulse Width High	50		ns
18	t _{BLC}	Byte Load Cycle Time	0.20	100	μs
19	t _{PLW}	Power-up To Write Operation		5	ms

* Valid for both Read and Write Cycles.







DEVICE OPERATION

READ: The DPE32X16A is accessed like a Static RAM. When \overline{CE} and \overline{OE} are low and \overline{WE} is high, the data stored at the memory location determined by address pins is asserted on the outputs. The outputs are put in the high impedance state whenever \overline{CE} or \overline{OE} is high. This dual line control gives designers flexibility in preventing bus contention.

WRITE: A low pulse on the \overline{WE} or \overline{CE} input with \overline{CE} or \overline{WE} low (respectively) and \overline{OE} high initiates a write cycle. The address is latched on the falling edge of \overline{CE} or \overline{WE} , whichever occurs last. The data is latched by the first rising edge of \overline{CE} or \overline{WE} . Once a BW* write has been started it will automatically time itself to completion.

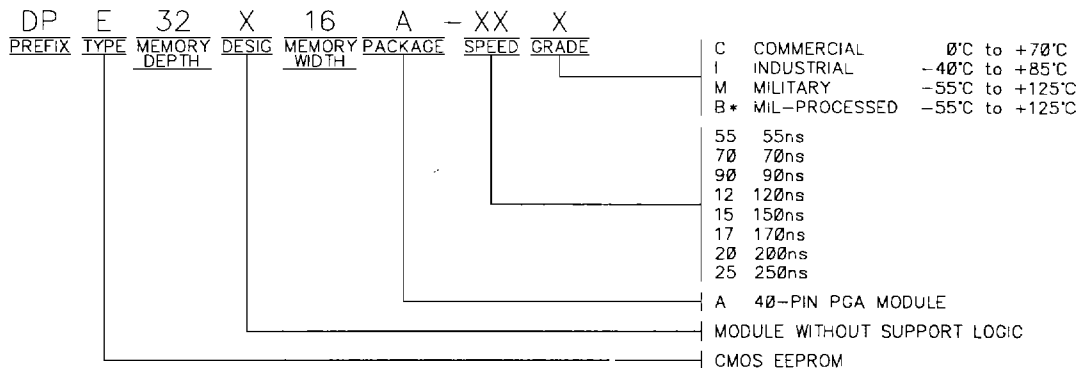
PAGE WRITE MODE: The page write operation of the DPE32X16A allows 1 to 64 BWs of data to be loaded into the device and then simultaneously written during the internal programming period. After the first data BW has been loaded into the device, successive BWs may be loaded in the same manner. Each new BW to be written must have its high to low transition on \overline{WE} (or \overline{CE}) within 100 μ s of the low to high

transition of \overline{WE} (or \overline{CE}) of the preceding BW. If a high to low transition is not detected within 100 μ s of the last low to high transition, the load period will end and the internal programming period will start. A6 to A14 specify the page address. The page address must be valid during each high to low transition of \overline{WE} (or \overline{CE}). A0 to A5 are used to specify which BWs within the page are to be written. The BWs may be loaded in any order and may be changed within the same load period. Only BWs which are specified for writing will be written; unnecessary cycling of other BWs within the page does not occur.

DATA POLLING: The DPE32X16A features DATA Polling to indicate the end of a write cycle. During a byte or page write cycle an attempted read of the last byte written will result in the compliment of the written data on I/O7 and/or I/O15. Once the the write cycle has been completed, true data is valid on all outputs, and the next cycle may begin. DATA Polling may begin at any time during the write cycle.

* Byte or Word

ORDERING INFORMATION

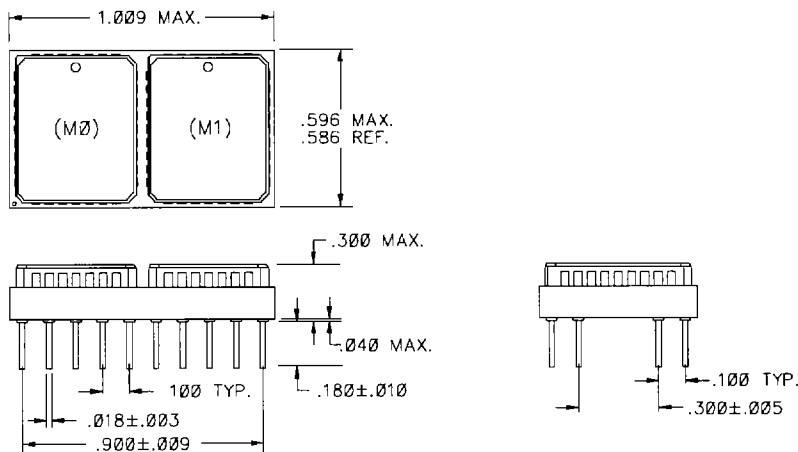


* B grade modules are constructed with 883 devices.

NOTES:

1. All voltages are with respect to V_{SS}.
2. -1.0V min. for pulse width less than 20ns (V_{IL} min. = -0.3V at DC level).
3. Stresses greater than those under **ABSOLUTE MAXIMUM RATINGS** may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
4. This parameter is guaranteed and not 100% tested.
5. Transition is measured at the point of ±500mV from steady state voltage.
6. When OE and CE are LOW and WE is HIGH, I/O pins are in the output state; and input signals of opposite phase to the outputs must not be applied.
7. The outputs are in a high impedance state when WE is LOW.

MECHANICAL DIAGRAMS



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